Product Specification

Number:L-KLS14-TCXO7050-12.8000-2.5-5V-BName:Quartz OscillatorCustomer:D02Date:2023-10-11

Customer Signature:	



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Compi Jenny	Jack.C		



Quartz Oscillator

REVISION RECORD

No	HISTORY	REASON	DATE
1	New	-	2023/10/11



Quartz Oscillator

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1 Parts explanation

It is mainly used in WLAN/WiMAX, Femtocell, Base Stations, Wireless Communications.

2 Reference Standard

- 3.1 MIL-STD-883H :Environmental tests' Mechanical tests.
- 3.2 MIL-STD-202: Test Methods for Electronic and Electrical component part.
- 3.3 IEC 60068-2 :Environmental tests' Mechanical tests.
- 3.4 ANSI/EIA-481-C: 8mm through 200mm enbossed carrier taping and 24mm punched
- 3.5 JEDEC J-STD-020C: Soldering

3 Title Guide

ORDER INFORMATION

L-KLS14-TCXO70	50-12.8000- 2.5-5V- <u>B</u>		
		Operating Temperature:	B:-20°C~+75°C
		voltage: 5V	
		Load Capacitance	
		Frequency:12.8000MHz	
		Serial Number	
		RoHS	



Quartz Oscillator

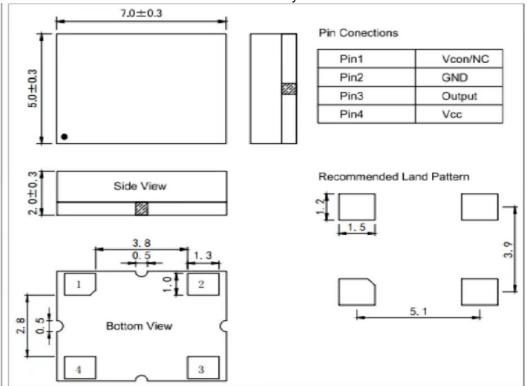
5 Performance

Electrical Performance. Electrical characteristics measured by S&A280.

No.	Item	Symb		Remark (Humidity:				
INO.	item	Symb.	Min.	Туре	Max.	Unit	40%~60%)	
1	Nominal Frequency	F0		12.800000		MHz	-	
2	Frequency Tolerance	-	-0.5	-	0.5	ppm	at 25±3℃	
3	Frequency Stability to temp	-	-2.5	-	2.5	ppm	-30~75℃	
4	Frequency Stability to Vdd	-	-0.3	-	0.3	ppm	Vdd±5%	
5	Frequency Stability to Aging	-	-1	-	1	ppm	First year	
6	Operating Temperature	T _{OPR}	-30	-	75	°C	-	
7	Storage Temperature	T _{STG}	-40	-	85	°C	at 25±3℃	
8	Supply Voltage	Vdd	4.5	5	5.5	V	-	
9	Current Consumption	I _{cc}	-	-	2	mA	-	
10	Frequency adjustment	-	±4	-	-	ppm	+1.5V ±1.0V	
11	Stability 24hrs after reflow	-	-1	-	1	ppm	-	
12	Output waveform	-	Clip	oped Sine Wa	ave	-	-	
13	Output Load	CL	1	10Kohm//10p	F	-	-	
14	Output Level	-	0.8	-	-	Vp-p	Clipped Sine Wave	
15	Start Time	S _T	-	-	3	mSec	-	
		-	-	-50	-	dBc/Hz	@ 1Hz	
16	Phase noise	-	-	-80	-	dBc/Hz	@ 10Hz	
	THOS HOSE	-	-	-125	-	dBc/Hz	@ 1KHz	
		-	-	-140	-	dBc/Hz	@ 100KHz	

6 Figure

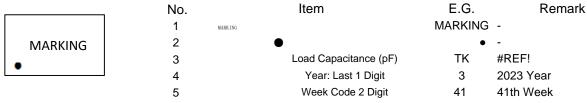
6.1 Product Dimensions and Solder Pad Layout Dimensions



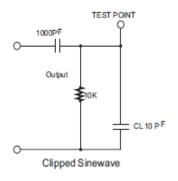


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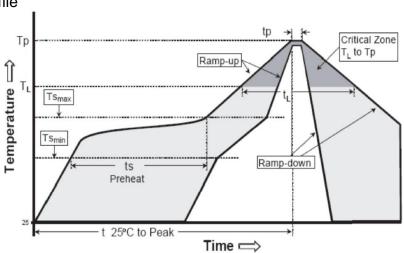
6.2 Marking



6.3 Measurement Circuit



7 IR Reflow Profile



Profiles Feature	Pb-Free Assembly
Average Ramp-up Rate (Ts max to Tp)	3°C/second max.
Preheat	
■Temperature Min (Ts min)	125℃
■Temperature Max (Ts max)	200℃
■Time (ts min to ts max)	60~180 seconds
Time maintained above	
■Temperature (T _L)	217℃
■Time (t _L)	60~150 seconds
Peak/Classification Temperature (T _p)	260℃
Time within 5℃ of actual Peak	20~40 seconds
Temperature (t _p)	
Ramp-down rate	6°C/second Max
Time 25℃ to Peak Temperature	8 minutes Max
Suggest reflow times	3 times

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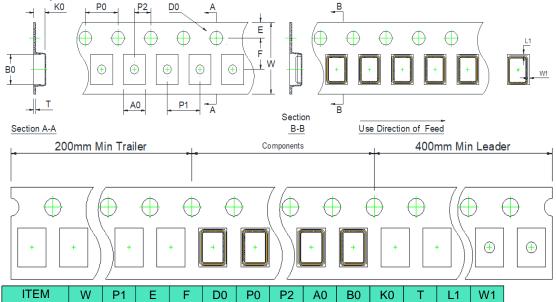


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8 Packing specification

Spec(mm)





8.2 Reel and Inner Box Dimensions and Q'ty

1.75

7.50

1.55

4.00

2.00 5.56

±0.30 ±0.10 ±0.22 ±0.10 ±0.10 ±0.10 ±0.10 ±0.10 ±0.10 ±0.10 ±0.05 ±0.05

7.85

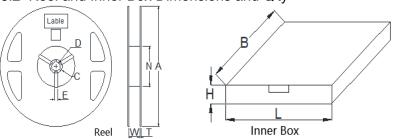
2.16

0.30

1.00

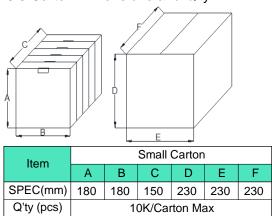
1.00

16.00 8.00



Item		Reel						Reel Inner			ner Bo	XC
item	Α	W	N	С	D	Е	Т	L	В	I		
SPEC(mm)	178	16.4	60.0	20.0	13.0	2.3	1.4	180	180	30		
Tol.(mm)	±2.0	±0.5	±0.5	±1.0	±0.5	±0.5	±0.2	-	-	-		
Q'ty (pcs)		1K/Reel Max						2K/	Box I	Иах		

8.3 Carton Dimensions and Q'ty





Quartz Oscillator

9 Reliability Test Item

No.	Item	Test Condition	Reference
1	Drop Test	Hight: 50cm Times: 2 times on hardWood	IEC68-2-32 Free Fall
2	Vibration	Frequency: 20 to2000Hz, full wave Amplitude: 1.5 mm (Peak to Peak) Sweep/Cycle: 2 minutes Accelerated Speed: 20g Direction: X, Y,Z Duration: 4min ,4 times in each direction	IEC68-2-6 Vibration
3	Solderability	Temperature: 235±5℃ Time: 10±1 Sec	MIL-STD-202 Method 210B Condition B
4	Aging	Temperature: 100℃ Time:168 hours	MIL-STD-883H Method 1008.2
5	Fine Leak	Helium Bombing:0.4~0.5Mpa Time:1 hour	MIL-STD-883H METHOD 1014.13
6	High Temperature Storage	Temperature: $85^{\circ}C \pm 5^{\circ}C$ Time 96 hours	IEC 60068-2-2
7	Temperature Cycle	Conditions: $25\% \pm 3\%$ for 10 minutes $-40\% \pm 3\%$ for 30 minutes $25\% \pm 3\%$ for 10 minutes $125\% \pm 3\%$ for 30 minutes 100 cycles	MIL-STD-883H METHOD 1010.8
8	Resistance to Soldering Heat	Pre-Heating:125°C 60~120 Sec Solder temperature: 260± 5°C Time: 20±5 sec	MIL-STD-202 Method 210B Condition B
9	Humidity	Temperature: $60^{\circ}C \pm 2^{\circ}C$ Relative Humidity: 95% Time: 96 hours.	IEC 60068-2-3 Damp Heat
10	Thermal shock	-40 °C ± 3 °C to 100 °C ± 3 °C, soak 15 minutes at each point, transfer time within 15 seconds, 20 cycles.	MIL-STD-883H METHOD 1011.9
11	Low Temperature Storage	Temperature: -40°C ±5°C Time: 96 hours	IEC 60068-2-1
12	IR Reflow	Pre-Heating:150℃ to 200℃, 60-120 Sec Heating:217℃, 60 to 150 Sec Peak temp:260℃±5℃,20±5 Sec Times: 2 times	JEDEC J-STD-020C
13	Salt Spray	Temperature: 35±2℃ Salinity: 5% Time:24hrs	MIL-STD-883H Method 1009.8 Condition A

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10 Product handling and control procedure

10.1 Precautions for storage

Storage of crystal units under higher temperature or high humidity for a long term may affects frequency stability or solderability. Please store the crystal units under the normal temperature and humidity without exposing to direct sunlight and dew condensation, and avoid the storage of crystal units for more than 6 months, and mount them as soon as possible after unpacking.

	Electrical Specification				
ltem -		Min.	Туре	Max.	Unit
Ctorogo poind	After customer assembly	15		-	Year
Storage peiod	Crystal unused	-		2	Year

10.2 Mounting of SMD Type products

When using an automatic loading machine, please test and confirm to cause no damage to the crystal units before mounting. Bending the circuit board in the process of cleaving boards after mounting and soldering crystal units may cause peeling off the soldering or package cracks by mechanical stress.

10.3 Ultrasonic cleaning

General cleaning solutions or ultrasonic cleaning method may be used to clean CREC's products. However, under certain circumstances, ultrasonic cleaning machine could generate resonance at the oscillaton frequency of our products and thus deteriorate the electrical characteristics in devices, and even damage the overall structure of devices. Therefore, verification test is recommended before cleaning.

10.4 Ultrasonic welding

Avoid mounting and processing by Ultrasonic welding this method has a possibility of an excessive vibration spreading inside the crystal products and becoming the cause of characteristic deterioration and not oscillating. If Ultrasonic welding is being used in process, please notify us in advance to verify it.

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